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Thin-Layer Micrometrology  
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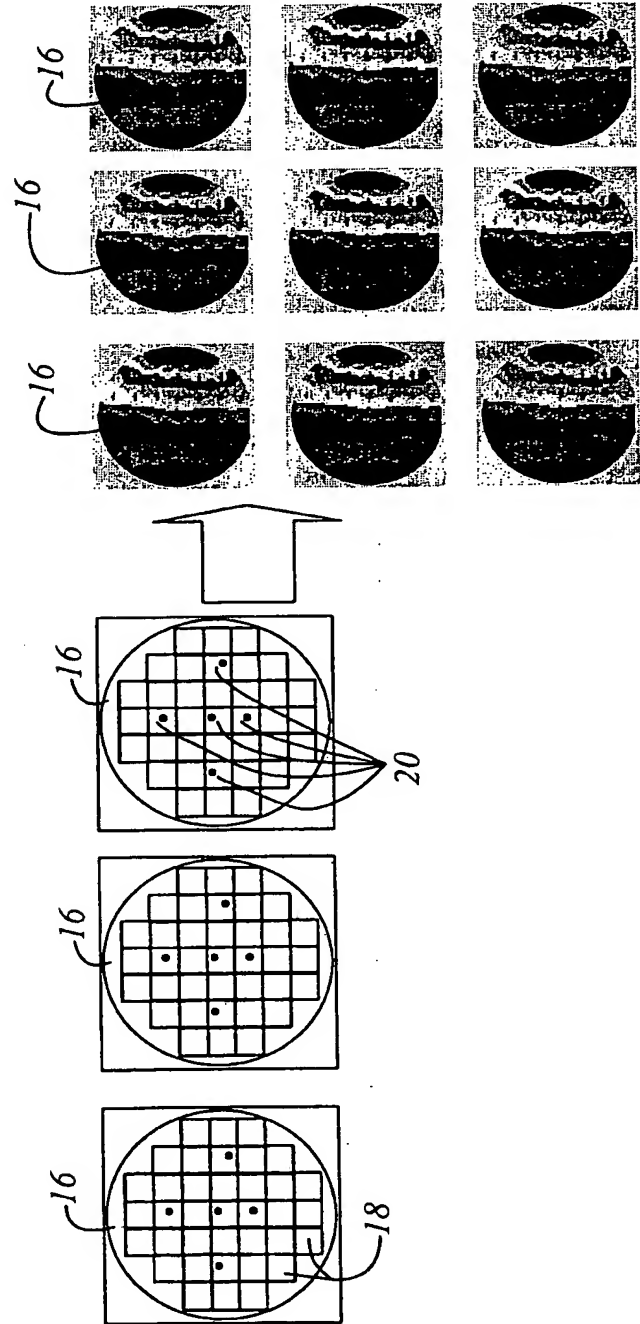
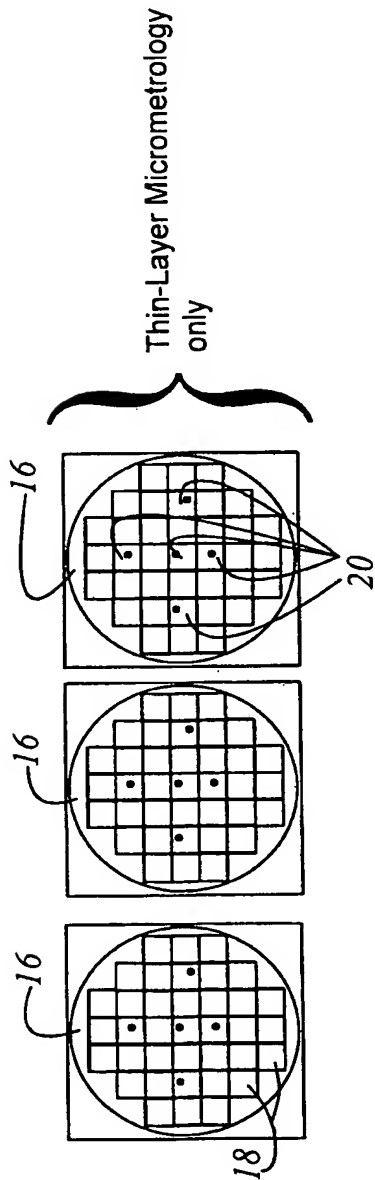


Fig. 5